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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/987,814	NITTA, TOSHIO	
Examiner	Art Unit	
Dei Jein	3664	

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INTERFERENCE SEARCHED			
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	DATE	EXMR
370/254,255,400,401,402,403,404,40 6,431,437,441,450,463 text search	8/19/2005	RJ
455/421,422.1,423,459,466 text search	8/19/2005	RJ
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